1.

Record Nr.	UNINA9910132411103321
Titolo	2013 8th IEEE Design and Test Symposium / / Institute of Electrical and Electronics Engineers
Pubbl/distr/stampa	Piscataway, New Jersey : , : Institute of Electrical and Electronics Engineers (IEEE), , 2013
ISBN	1-4799-3525-5
Descrizione fisica	1 online resource : illustrations
Disciplina	621
Soggetti	Electronic circuit design Integrated circuits - Testing Electronic circuits - Testing
Lingua di pubblicazione	Inglese
Formato	Materiale a stampa
Livello bibliografico	Monografia
Sommario/riassunto	The International Design and Test Symposium explores emerging challenges and novel concepts in design, automation, test and reliability of electronic products ranging from integrated circuits through multi chip modules and printed circuit boards to full systems and microsystems IDT provides unique forum to discuss best practices and novel ideas in design methods, tools, test and reliability in the Middle East and Africa (MEA) region.